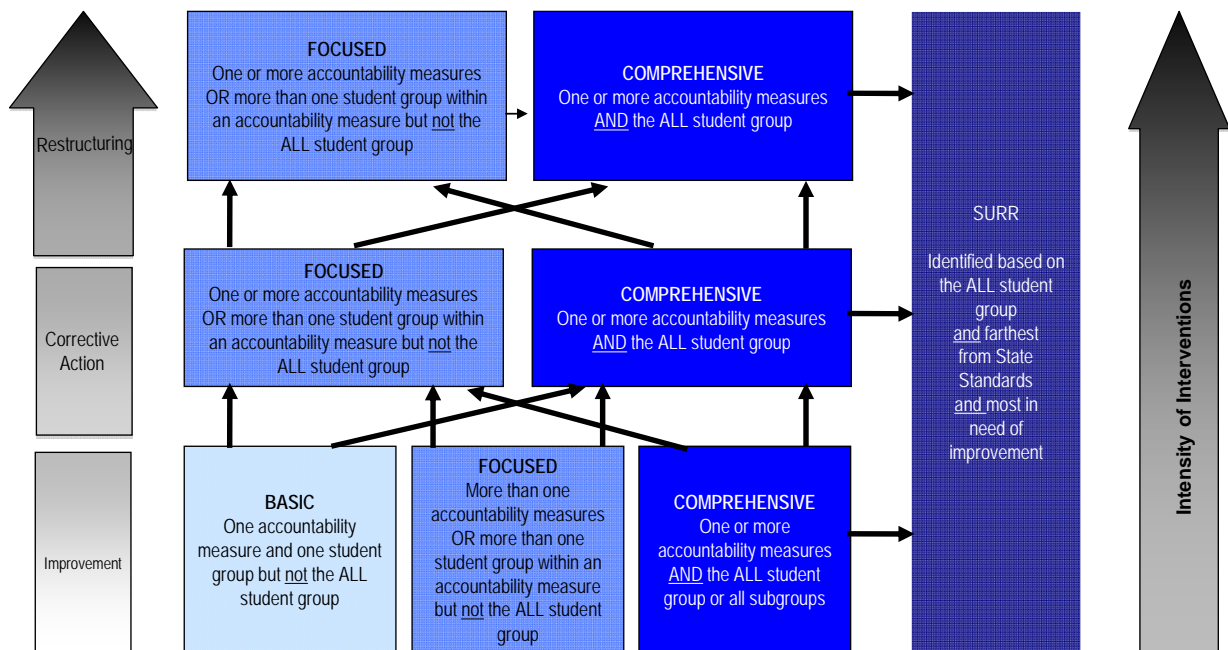


Differentiated Accountability Overview

The USDOE has approved New York's **Differentiated Accountability Pilot**. The plan is effective for 2009-10 through 2012-13. The SED maintains that this plan will allow better allocation of resources and, ultimately, increase in the number of schools making AYP. The stated goals of the plan include:

- Reducing the number of School accountability distinctions from 17 to 8.
- Allowing for differentiation in the improvement process.
- Increasing alignment between state and federal rules.
- Maximizing limited resources.
- Shifting Supplemental Education Services (SES) requirements to a school's first year of improvement identification and shift Public School Choice (PSC) to after an identified school has failed to make AYP.

The model creates **three phases** of improvement for schools that fail to make AYP: Improvement, Corrective Action, and Restructuring. The improvement phase is the least intensive phase; restructuring is the most intensive (except for SURR which will continue to be used by SED for schools in dramatic need of improvement). This chart shows how the phases progress from least intensive at the bottom to most intensive at the top:



A school moves from one phase of the plan to the next when it fails to make AYP for two consecutive years. Similarly, two years of meeting AYP is required to discontinue identification. The rigor of the interventions and amount of oversight increases as a school moves from one phase to the next.

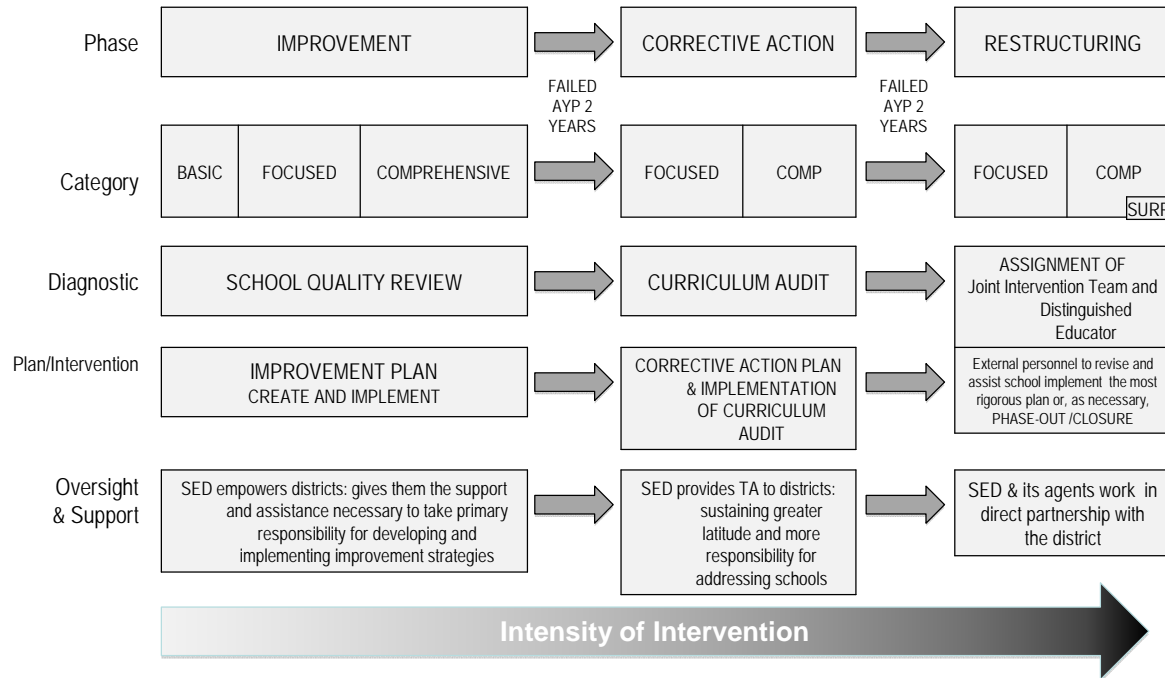
Within the phases there is differentiation into **categories**: basic, focused, and comprehensive. In the least intensive phase (Improvement), a school might be in the basic, focused, or comprehensive category. This distinction depends on whether it is a single disaggregated group that is not making AYP, if multiple groups are involved, or if it is the all student group. In the Corrective Action and Restructuring phases there are only two categories (focused or comprehensive).

The phases and categories will replace previous labels and designations such as SINI, SRAP, etc. In the new scheme, schools would be identified by the category inside the phase. This is an integration of the present, dual Title I and non-Title I system, but SES and PSC continue to apply to Title I schools only. Note: this system applies to schools and not districts at this time.

The idea of the three categories is to allow schools and districts flexibility in school improvement planning that reflects the specific situation in each school. Improvement plans, especially in the basic and focused categories, can reflect greater targeting of specific school populations.

If the failure of groups to make AYP persists or becomes more widespread, SED may use other provisions of Chapter 57 which require the assignment of School Quality Review Teams, Joint Intervention teams, or Distinguished Educators.

Here is another look at the model:



During the transition to the new plan, **schools that have been previously identified** will move from their current accountability status into one of the phases (and categories) in the new model. The number of years that a school has failed to make AYP will determine in which phase in the new model the school is placed. Identified schools that made AYP or are entering the second year will continue to implement the intervention they are already doing (the two-year cycle premise remains in effect). There is a table in the complete pilot proposal (see link below) that details the transition of categories from 2008-2009 status to the differentiated model.

There are a number of resources provided by SED to further explain the Differentiated Accountability Pilot Program (accessible at <http://www.emsc.nysed.gov/nyc/DifferentiatedAccountability/DifferenAccthp.shtml>) by using the hotlinks below:

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- The February, 2009, [memo from SED](#) announcing federal approval
- An [overview](#) of the system
- A [ppt presentation](#) from SED that describes the program
- The [complete pilot proposal](#) as presented to the USDOE